

# 1EDI EiceDRIVER™ Compact

## Separate output variant for MOSFET

Single Channel MOSFET Gate Driver IC

1EDI60N12AF

## Data Sheet

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Industrial Power Control

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## 1EDI EiceDRIVER™ Compact Single Channel MOSFET Gate Driver IC

Separate output  
variant for MOSFET

### 1 Overview

#### Main Features

- Single channel isolated MOSFET Driver
- Input to output isolation voltage up to 1200 V
- For high voltage power MOSFETs
- Up to 10 A typical peak current at rail-to-rail outputs
- Separate source and sink outputs

#### Product Highlights

- Galvanically isolated Coreless Transformer Driver
- Wide input voltage operating range
- Low input to output capacitive coupling
- Suitable for operation at high ambient temperature

#### Typical Application

- AC and Brushless DC Motor Drives
- High Voltage PFC, DC/DC-Converter and DC/AC-Inverter
- Induction Heating Resonant Application
- UPS-Systems
- Welding
- Solar MPPT boost converter

#### Description

The 1EDI60N12AF is a galvanically isolated single channel MOSFET driver in a PG-DSO-8-51 package that provides output currents of at least 6 A at separated output pins.

The input logic pins operate on a wide input voltage range from 3 V to 15 V using CMOS threshold levels to support even 3.3 V microcontroller.

Data transfer across the isolation barrier is realized by the Coreless Transformer Technology.

Every driver family member comes with logic input and driver output under voltage lockout (UVLO) and active shutdown.



| Product Name | Gate Drive Current (min)      | Package     |
|--------------|-------------------------------|-------------|
| 1EDI60N12AF  | ±6.0 A MOSFET level optimized | PG-DSO-8-51 |

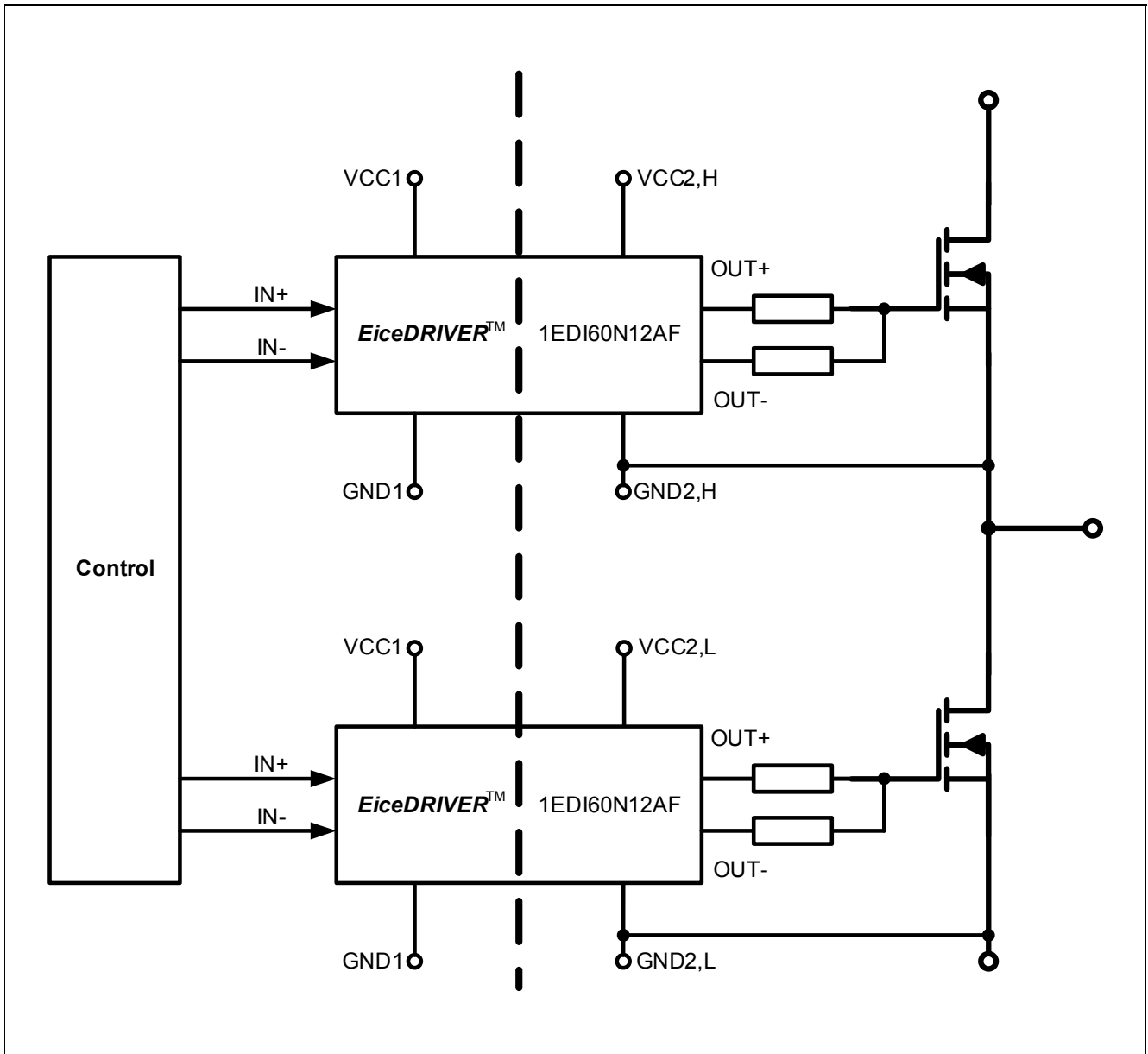


Figure 1 Typical Application



## 2 Block Diagram

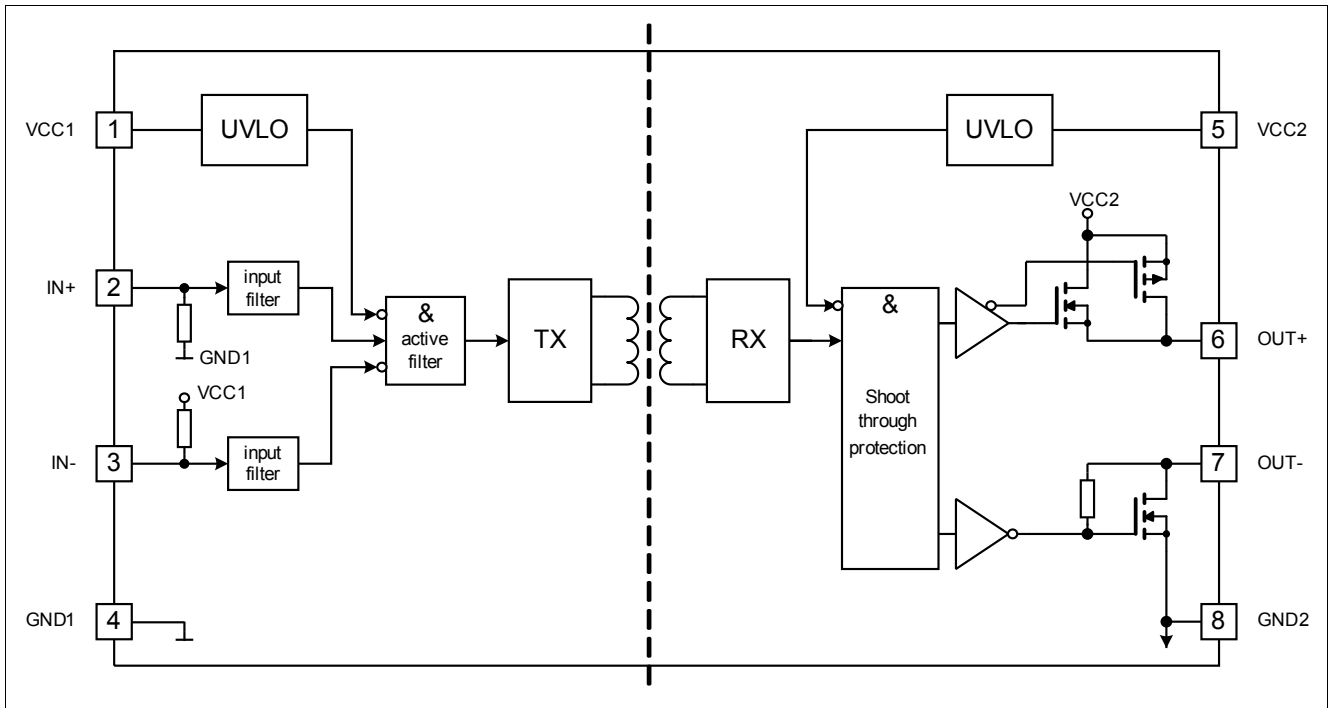


Figure 2 Block Diagram 1EDI60N12AF

### 3 Pin Configuration and Functionality

#### 3.1 Pin Configuration

Table 1 Pin Configuration

| Pin No. | Name | Function                                |
|---------|------|---|
| 1       | VCC1 | Positive Logic Supply                   |
| 2       | IN+  | Non-Inverted Driver Input (active high) |
| 3       | IN-  | Inverted Driver Input (active low)      |
| 4       | GND1 | Logic Ground                            |
| 5       | VCC2 | Positive Power Supply Output Side       |
| 6       | OUT+ | Driver Source Output                    |
| 7       | OUT- | Driver Sink Output                      |
| 8       | GND2 | Power Ground                            |

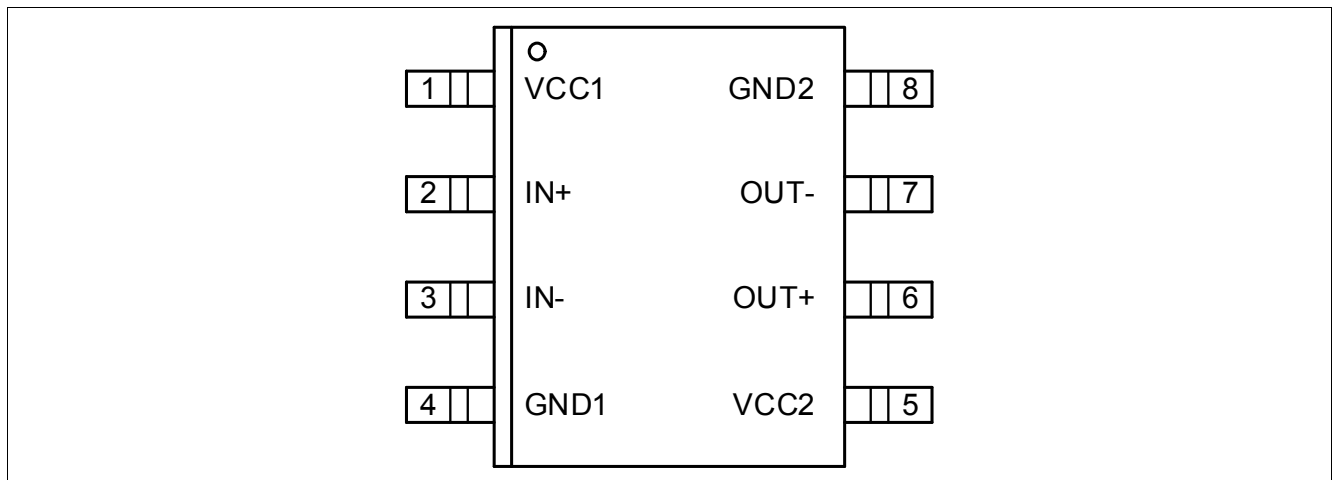


Figure 3 PG-DSO-8-51 (top view)

#### 3.2 Pin Functionality

##### VCC1

Logic input supply voltage of 3.3 V up to 15 V wide operating range.

##### IN+ Non Inverting Driver Input

IN+ non-inverted control signal for driver output if IN- is set to low. (Output sourcing active at IN+ = high and IN- = low)

Due to internal filtering a minimum pulse width is defined to ensure robustness against noise at IN+. An internal weak pull-down-resistor favors off-state.

**IN- Inverting Driver Input**

IN- inverted control signal for driver output if IN+ is set to high. (Output sourcing active at IN- = low and IN+ = high)  
Due to internal filtering a minimum pulse width is defined to ensure robustness against noise at IN-. An internal weak pull-up-resistor favors off-state.

**GND1**

Ground connection of input circuit.

**VCC2**

Positive power supply pin of output driving circuit. A proper blocking capacitor has to be placed close to this supply pin.

**OUT+ Driver Source Output**

Driver source output pin to turn on external MOSFET. During on-state the driving output is switched to VCC2. Switching of this output is controlled by IN+ and IN-. This output will also be turned off at an UVLO event.

During turn off the OUT+ terminal is able to sink approx. 100 mA.

**OUT- Driver Sink Output)**

Driver sink output pin to turn off external MOSFET. During off-state the driving output is switched to GND2. Switching of this output is controlled by IN+ and IN-. In case of UVLO an active shut down keeps the output voltage at a low level.

**GND2 Reference Ground**

Reference ground of the output driving circuit.

In case of a bipolar supply (positive and negative voltage in reference to the MOSFET source) this pin is connected to the negative supply voltage.

## 4 Functional Description

### 4.1 Introduction

The 1EDI EiceDRIVER™ Compact is a general purpose MOSFET gate driver. Basic control and protection features support fast and easy design of highly reliable systems.

The integrated galvanic isolation between control input logic and driving output stage grants additional safety. Its wide input voltage supply range support the direct connection of various signal sources like DSPs and microcontrollers.

The separated rail-to-rail driver outputs simplify gate resistor selection, save an external high current bypass diode and enhance dV/dt control.

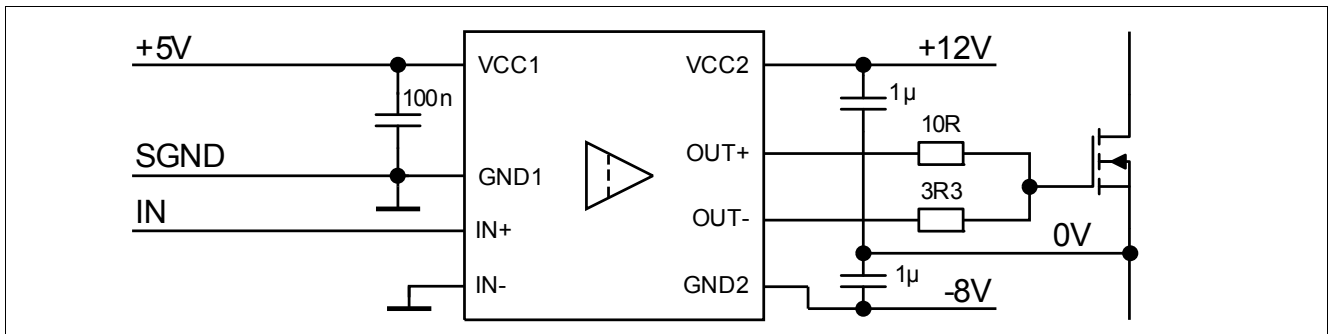


Figure 4 Application Example Bipolar Supply

### 4.2 Supply

The driver can operate over a wide supply voltage range, either unipolar or bipolar.

With bipolar supply the driver is typically operated with a positive voltage of 12 V at VCC2 and a negative voltage of -8 V at GND2 relative to the source of the MOSFET as seen in [Figure 4](#). Negative supply can help to prevent a dynamic turn on of the MOSFET.

For unipolar supply configuration the driver is typically supplied with a positive voltage of 12 V at VCC2. In this case, careful evaluation for turn off gate resistor selection is recommended to avoid dynamic turn on (see [Figure 5](#)).

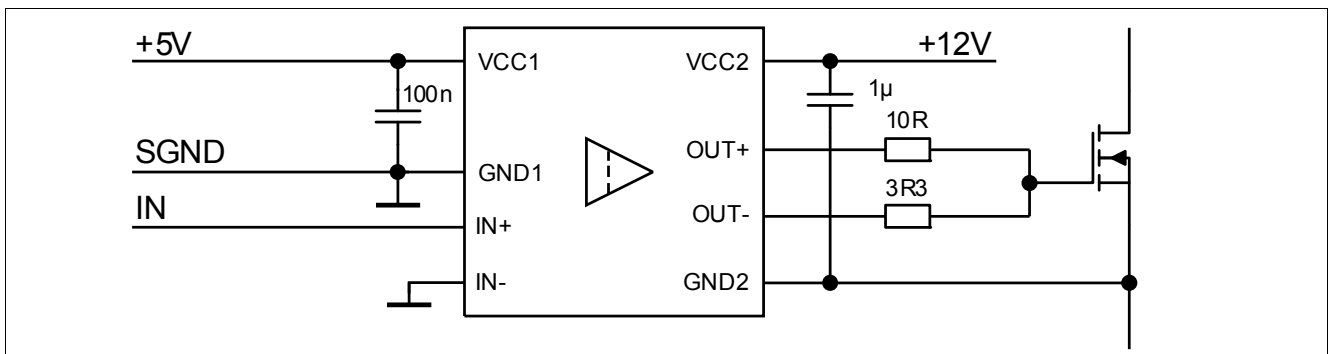


Figure 5 Application Example Unipolar Supply

## 4.3 Protection Features

### 4.3.1 Undervoltage Lockout (UVLO)

To ensure correct switching of MOSFETs the device is equipped with an undervoltage lockout for input and output independently. Operation starts only after both VCC levels have increased beyond the respective  $V_{UVLOH}$  levels (see also [Figure 8](#)).

If the power supply voltage  $V_{VCC1}$  of the input chip drops below  $V_{UVLOL1}$  a turn-off signal is sent to the output chip before power-down. The MOSFET is switched off and the signals at IN+ and IN- are ignored until  $V_{VCC1}$  reaches the power-up voltage  $V_{UVLOH1}$  again.

If the power supply voltage  $V_{VCC2}$  of the output chip goes down below  $V_{UVLOL2}$  the MOSFET is switched off and signals from the input chip are ignored until  $V_{VCC2}$  reaches the power-up voltage  $V_{UVLOH2}$  again.

*Note:  $V_{VCC2}$  is always referred to GND2 and does not differentiate between unipolar or bipolar supply.*

### 4.3.2 Active Shut-Down

The Active Shut-Down feature ensures a safe MOSFET off-state if the output chip is not connected to the power supply, MOSFET gate is clamped at OUT- to GND2.

### 4.3.3 Short Circuit Clamping

During short circuit the MOSFET's gate voltage tends to rise because of the feedback via the Miller capacitance. An additional protection circuit connected to OUT+ limits this voltage to a value slightly higher than the supply voltage. A maximum current of 500 mA may be fed back to the supply through this path for 10  $\mu$ s. If higher currents are expected or tighter clamping is desired external Schottky diodes may be added.

## 4.4 Non-Inverting and Inverting Inputs

There are two possible input modes to control the MOSFET. At non-inverting mode IN+ controls the driver output while IN- is set to low. At inverting mode IN- controls the driver output while IN+ is set to high, please see [Figure 7](#). A minimum input pulse width is defined to filter occasional glitches.

## 4.5 Driver Outputs

The output driver section uses MOSFETs to provide a rail-to-rail output. This feature permits that tight control of gate voltage during on-state and short circuit can be maintained as long as the driver's supply is stable. Due to the low internal voltage drop, switching behaviour of the MOSFET is predominantly governed by the gate resistor. Furthermore, it reduces the power to be dissipated by the driver.

## 5 Electrical Parameters

### 5.1 Absolute Maximum Ratings

Note: Absolute maximum ratings are defined as ratings, which when being exceeded may lead to destruction of the integrated circuit. Unless otherwise noted all parameters refer to GND1.

**Table 2 Absolute Maximum Ratings**

| Parameter                                | Symbol          | Values         |                | Unit | Note / Test Condition          |
|--|-----------------|----------------|----------------|------|--------------------------------|
|  |                 | Min.           | Max.           |      |                                |
| Power supply output side                 | $V_{VCC2}$      | -0.3           | 40             | V    | 1)                             |
| Gate driver output                       | $V_{OUT}$       | $V_{GND2}-0.3$ | $V_{VCC2}+0.3$ | V    | –                              |
| Positive power supply input side         | $V_{VCC1}$      | -0.3           | 18.0           | V    | –                              |
| Logic input voltages (IN+,IN-)           | $V_{LogicIN}$   | -0.3           | 18.0           | V    | –                              |
| Input to output isolation voltage (GND2) | $V_{ISO}$       | -1200          | 1200           | V    |                                |
| Junction temperature                     | $T_J$           | -40            | 150            | °C   | –                              |
| Storage temperature                      | $T_S$           | -55            | 150            | °C   | –                              |
| Power dissipation (Input side)           | $P_{D, IN}$     | –              | 25             | mW   | 2) @ $T_A = 25^\circ\text{C}$  |
| Power dissipation (Output side)          | $P_{D, OUT}$    | –              | 400            | mW   | 2) @ $T_A = 25^\circ\text{C}$  |
| Thermal resistance (Input side)          | $R_{THJA, IN}$  | –              | 145            | K/W  | 2) @ $T_A = 85^\circ\text{C}$  |
| Thermal resistance (Output side)         | $R_{THJA, OUT}$ | –              | 165            | K/W  | 2) @ $T_A = 85^\circ\text{C}$  |
| ESD capability                           | $V_{ESD, HBM}$  | –              | 2              | kV   | Human Body Model <sup>3)</sup> |

1) With respect to GND2.

2) See [Figure 10](#) for reference layouts for these thermal data. Thermal performance may change significantly with layout and heat dissipation of components in close proximity.

3) According to EIA/JESD22-A114-C (discharging a 100 pF capacitor through a 1.5 kΩ series resistor).

## 5.2 Operating Parameters

Note: Within the operating range the IC operates as described in the functional description. Unless otherwise noted all parameters refer to GND1.

**Table 3 Operating Parameters**

| Parameter                             | Symbol          | Values |      | Unit              | Note / Test Condition         |
|---------------------------------------|-----------------|--------|------|-------------------|-------------------------------|
|                                       |                 | Min.   | Max. |                   |                               |
| Power supply output side              | $V_{VCC2}$      | 10     | 35   | V                 | 1)                            |
| Power supply input side               | $V_{VCC1}$      | 3.1    | 17   | V                 | –                             |
| Logic input voltages (IN+, IN-)       | $V_{LogicIN}$   | -0.3   | 17   | V                 | –                             |
| Switching frequency                   | $f_{sw}$        | –      | 4.0  | MHz               | 2) 3)                         |
| Ambient temperature                   | $T_A$           | -40    | 125  | °C                | –                             |
| Thermal coefficient, junction-top     | $\Psi_{th,jt}$  | –      | 4.8  | K/W               | 3) @ $T_A = 85^\circ\text{C}$ |
| Common mode transient immunity (CMTI) | $ dV_{ISO}/dt $ | –      | 100  | kV/ $\mu\text{s}$ | 3) @ 1000 V                   |

1) With respect to GND2.

2) do not exceed max. power dissipation

3) Parameter is not subject to production test - verified by design/characterization

## 5.3 Electrical Characteristics

Note: The electrical characteristics include the spread of values in supply voltages, load and junction temperatures given below. Typical values represent the median values at  $T_A = 25^\circ\text{C}$ . Unless otherwise noted all voltages are given with respect to their respective GND (GND1 for pins 1 to 3, GND2 for pins 5 to 7).

### 5.3.1 Voltage Supply

**Table 4 Voltage Supply**

| Parameter   | Symbol       | Values |      |      | Unit | Note / Test Condition |
|---|--------------|--------|------|------|------|-----------------------|
|   |              | Min.   | Typ. | Max. |      |                       |
| UVLO threshold input chip                                 | $V_{UVLOH1}$ | –      | 2.85 | 3.1  | V    | –                     |
|   | $V_{UVLOL1}$ | 2.55   | 2.75 | –    | V    | –                     |
| UVLO hysteresis input chip ( $V_{UVLOH1} - V_{UVLOL1}$ )  | $V_{HYS1}$   | 90     | 100  | –    | mV   | –                     |
| UVLO threshold output chip (MOSFET Supply)                | $V_{UVLOH2}$ | –      | 9.1  | 10.0 | V    | –                     |
|   | $V_{UVLOL2}$ | 8.0    | 8.5  | –    | V    | –                     |
| UVLO hysteresis output chip ( $V_{UVLOH2} - V_{UVLOL2}$ ) | $V_{HYS2}$   | 550    | 600  | –    | mV   | –                     |

**Table 4 Voltage Supply (cont'd)**

| Parameter                     | Symbol   | Values |      |      | Unit | Note / Test Condition  |
|-------------------------------|----------|--------|------|------|------|--|
|                               |          | Min.   | Typ. | Max. |      |  |
| Quiescent current input chip  | $I_{Q1}$ | –      | 0.65 | 1.0  | mA   | $V_{VCC1} = 5\text{ V}$<br>IN+ = High,<br>IN- = Low<br>=>OUT = High  |
| Quiescent current output chip | $I_{Q2}$ | –      | 1.2  | 2.0  | mA   | $V_{VCC2} = 15\text{ V}$<br>IN+ = High,<br>IN- = Low<br>=>OUT = High |

### 5.3.2 Logic Input

Note: Unless stated otherwise  $V_{CC1} = 5.0\text{V}$

**Table 5 Logic Input**

| Parameter                  | Symbol               | Values |      |      | Unit          | Note / Test Condition   |
|----------------------------|----------------------|--------|------|------|---------------|-------------------------|
|                            |                      | Min.   | Typ. | Max. |               |                         |
| IN+,IN- low input voltage  | $V_{IN+L}, V_{IN-L}$ | –      | –    | 30   | %             | of VCC1                 |
| IN+,IN- high input voltage | $V_{IN+H}, V_{IN-H}$ | 70     | –    | –    | %             | of VCC1                 |
| IN+,IN- low input voltage  | $V_{IN+L}, V_{IN-L}$ | –      | –    | 1.5  | V             | –                       |
| IN+,IN- high input voltage | $V_{IN+H}, V_{IN-H}$ | 3.5    | –    | –    | V             | –                       |
| IN- input current          | $I_{IN-}$            | –      | 70   | 200  | $\mu\text{A}$ | $V_{IN-} = \text{GND1}$ |
| IN+ input current          | $I_{IN+}$            | –      | 70   | 200  | $\mu\text{A}$ | $V_{IN+} = V_{CC1}$     |

### 5.3.3 Gate Driver

**Table 6 Gate Driver**

| Parameter                                     | Symbol          | Values |           |      | Unit | Note / Test Condition                                       |
|---|-----------------|--------|-----------|------|------|---|
|   |                 | Min.   | Typ.      | Max. |      |   |
| High level output peak current<br>1EDI60N12AF | $I_{OUT+,PEAK}$ | 6.0    | –<br>10.0 | –    | A    | 1)<br>IN+ = High,<br>IN- = Low,<br>$V_{VCC2} = 15\text{ V}$ |
| Low level output peak current<br>1EDI60N12AF  | $I_{OUT-,PEAK}$ | 6.0    | –<br>9.4  | –    | A    | 1)<br>IN+ = Low,<br>IN- = Low,<br>$V_{VCC2} = 15\text{ V}$  |

1) voltage across the device  $V_{(VCC2 - OUT+)}$  or  $V_{(OUT- - GND2)} < V_{VCC2}$ .



### 5.3.4 Short Circuit Clamping

**Table 7 Short Circuit Clamping**

| Parameter   | Symbol       | Values |      |      | Unit | Note / Test Condition  |
|---|--------------|--------|------|------|------|--|
|   |              | Min.   | Typ. | Max. |      |  |
| Clamping voltage (OUT+)<br>( $V_{OUT} - V_{VCC2}$ ) | $V_{CLPout}$ | –      | 0.9  | 1.3  | V    | IN+ = High,<br>IN- = Low,<br>OUT = High<br>$I_{OUT} = 500$ mA<br>pulse test,<br>$t_{CLPmax} = 10$ $\mu$ s) |

### 5.3.5 Dynamic Characteristics

Dynamic characteristics are measured with  $V_{VCC1} = 5$  V and  $V_{VCC2} = 15$  V.

**Table 8 Dynamic Characteristics**

| Parameter   | Symbol                         | Values |      |      | Unit | Note / Test Condition   |
|---|--------------------------------|--------|------|------|------|---|
|   |                                | Min.   | Typ. | Max. |      |   |
| Input IN to output propagation delay ON   | $T_{PDON}$                     | 95     | 120  | 142  | ns   | $C_{LOAD} = 100$ pF<br>$V_{IN+} = 50\%$ ,<br>$V_{OUT} = 50\%$ @ 25°C        |
| Input IN to output propagation delay OFF  | $T_{PDOFF}$                    | 105    | 125  | 150  | ns   |   |
| Input IN to output propagation delay distortion<br>( $T_{PDOFF} - T_{PDON}$ )                       | $T_{PDISTO}$                   | -15    | 5    | 25   | ns   |   |
| Input pulse suppression<br>IN+, IN-   | $T_{MININ+}$ ,<br>$T_{MININ-}$ | 30     | 40   | –    | ns   | –   |
| IN input to output propagation delay ON variation due to temp                                       | $T_{PDONT}$                    | –      | –    | 10   | ns   | <sup>1)</sup> $C_{LOAD} = 100$ pF<br>$V_{IN+} = 50\%$ ,<br>$V_{OUT} = 50\%$ |
| IN input to output propagation delay OFF variation due to temp                                      | $T_{PDOFFt}$                   | –      | –    | 10   | ns   | <sup>1)</sup> $C_{LOAD} = 100$ pF<br>$V_{IN+} = 50\%$ ,<br>$V_{OUT} = 50\%$ |
| IN input to output propagation delay distortion variation due to temp<br>( $T_{PDOFF} - T_{PDON}$ ) | $T_{PDISTOt}$                  | –      | –    | 4    | ns   | <sup>1)</sup> $C_{LOAD} = 100$ pF<br>$V_{IN+} = 50\%$ ,<br>$V_{OUT} = 50\%$ |
| Rise time   | $T_{RISE}$                     | 5      | 10   | 20   | ns   | $C_{LOAD} = 1$ nF<br>$V_L 20\%$ , $V_H 80\%$                                |
| Fall time   | $T_{FALL}$                     | 4      | 9    | 19   | ns   | $C_{LOAD} = 1$ nF<br>$V_L 20\%$ , $V_H 80\%$                                |

1) The parameter is not subject to production test - verified by design/characterization

### 5.3.6 Active Shut Down

Table 9 Active Shut Down

| Parameter                | Symbol           | Values |      |      | Unit | Note / Test Condition                          |
|--------------------------|------------------|--------|------|------|------|--|
|                          |                  | Min.   | Typ. | Max. |      |  |
| Active shut down voltage | $V_{ACTSD}^{1)}$ | –      | 2.2  | 2.5  | V    | $I_{OUT}/I_{OUT,PEAK}=0.1$ ,<br>$V_{CC2}$ open |

1) Referred to GND2

## 6 Timing Diagramms

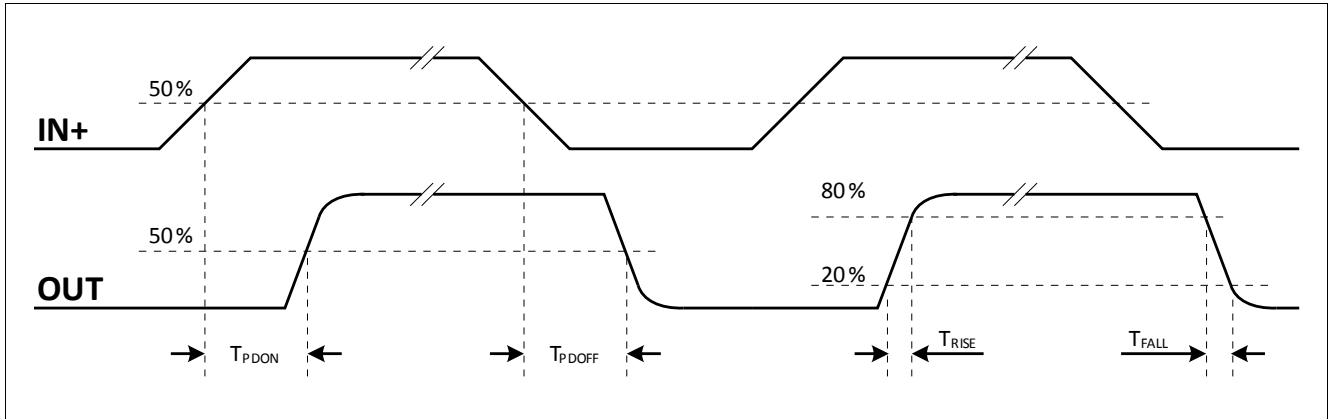


Figure 6 Propagation Delay, Rise and Fall Time

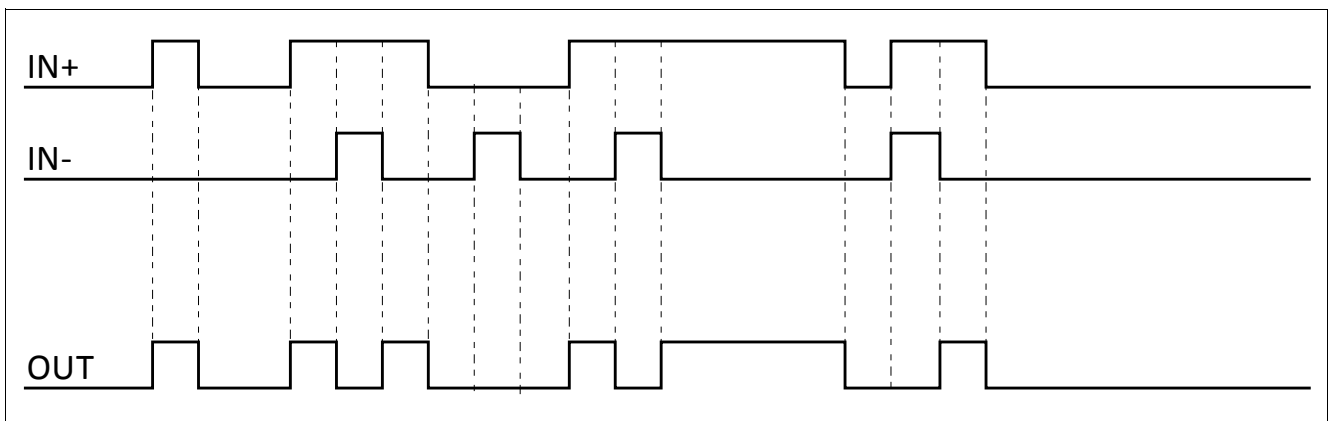


Figure 7 Typical Switching Behavior

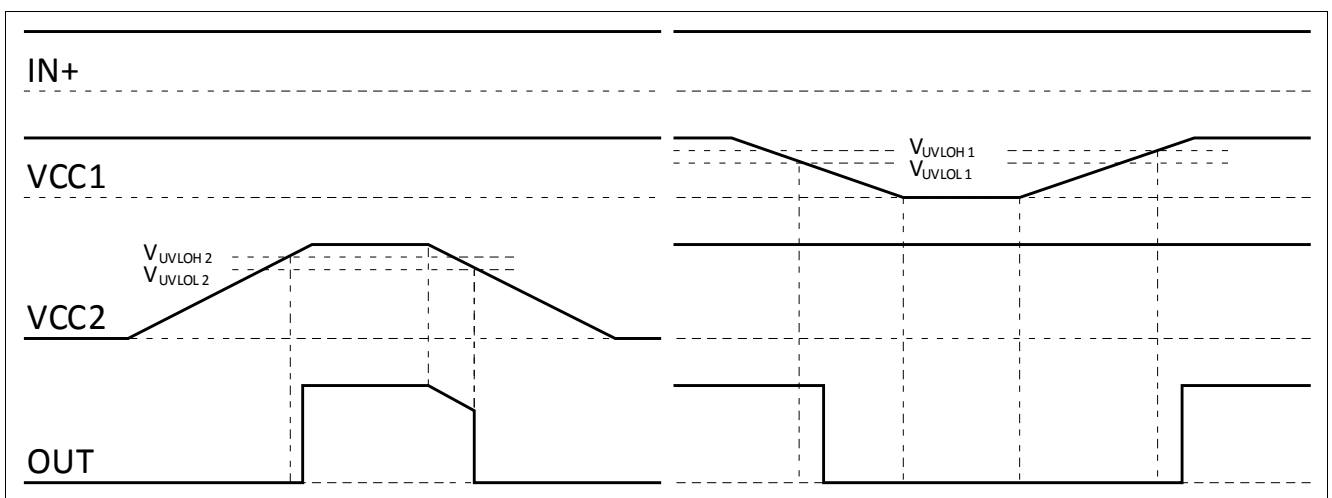


Figure 8 UVLO Behavior

7 Package Outlines



Figure 9 PG-DSO-8-51 (Plastic (Green) Dual Small Outline Package)

## 8 Application Notes

### 8.1 Reference Layout for Thermal Data

The PCB layout shown in **Figure 10** represents the reference layout used for the thermal characterisation. Pin 4 (GND1) and pin 8 (GND2) require each a ground plane of 100 mm<sup>2</sup> for achieving maximum power dissipation. The Separate output variant for MOSFET is conceived to dissipate most of the heat generated through these pins.

The thermal coefficient junction-top ( $\Psi_{th,jt}$ ) can be used to calculate the junction temperature at a given top case temperature and driver power dissipation:

$$T_j = \Psi_{th,jt} \cdot P_D + T_{top}$$



**Figure 10** Reference Layout for Thermal Data (Copper thickness 35 µm)

### 8.2 Printed Circuit Board Guidelines

The following factors should be taken into account for an optimum PCB layout.

- Sufficient spacing should be kept between high voltage isolated side and low voltage side circuits.
- The same minimum distance between two adjacent high-side isolated parts of the PCB should be maintained to increase the effective isolation and to reduce parasitic coupling.
- In order to ensure low supply ripple and clean switching signals, bypass capacitor trace lengths should be kept as short as possible.

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